

F-6971

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		Document Number	Date	Country	Class	Subclass	Translation
							Yes No
TRANSLATION KEY: * English Abstract. ^a Concise statement of relevance provided in foreign search report. ^c Concise statement of relevance provided in specification. ^b Concise statement of relevance provided in IDS. ^p Relevant portion of reference translated. ^o English abstract only - copy of reference in pct search.							
OTHER INFORMATION DISCLOSURE CITATIONS (Including Author, Title, Date, Pertinent Pages, Etc.)							
HKS		1997 - X-ray Reflectometer for the Diagnostics of Thin Films During Growth, U. Niggemeier, K. Lischka, W. M. Plotz and V. Holy, Journal of Applied Crystallography, Volume 30, Pages 905-908					
EXAMINER Hoon K. Song				DATE CONSIDERED 2/13/05			
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